



CALL FOR PAPERS

ICIBMCEEM 2020
Apr 23-24, 2020
Tokyo, Japan

The International Research Conference is a federated organization dedicated to bringing together a significant number of diverse scholarly events for presentation within the conference program. Events will run over a span of time during the conference depending on the number and length of the presentations.

ICIBMCEEM 2020 : International Conference on Imaging Based Material Characterization of Electronics and Electron Microscope is the premier interdisciplinary forum for the presentation of new advances and research results in the fields of Imaging Based Material Characterization of Electronics and Electron Microscope. The conference will bring together leading academic scientists, researchers and scholars in the domain of interest from around the world. Topics of interest for submission include, but are not limited to:

Complex/functional materials
New imaging method development,
Combination of multiple
supplemental characterization
Eco-design, Recycling, Material
Processing
Process
optimization/intensification
Multiphase flows (e.g. liquid-gas
flows, liquid-solid flows)
Neutrons, X-rays

In-situ/Operando measurement
Tomography/radiography
Magnetic resonance imaging
Automated image analysis
Electron microscope (e.g. SEM, TEM)